ABSTRACT

A fast-test printed resistor device with test auxiliary lines on a printed circuit substrate is disclosed. The resistor device comprises at least one first printed circuit foil; at least one second printed circuit foil; a first carbon film resistor sheet connected to the at least one first printed circuit foil; a second carbon film resistor sheet connected to the at least one second printed circuit foil; a first test auxiliary line connected to the first carbon film resistor sheet; and a second test auxiliary line connected to the carbon film resistor sheet; a gap being formed between the first and second test auxiliary lines. One end of each of the two test auxiliary lines is connected to an edge of a respect one of the two carbon film resistor sheets and another end of the test auxiliary line is extended out with a predetermined length for testing.